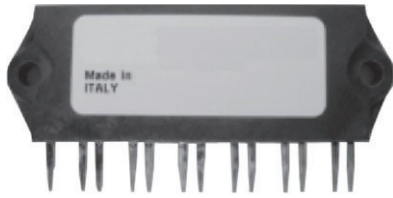


## IGBT SIP Module (Short Circuit Rated Ultrafast IGBT)



IMS-2

| PRIMARY CHARACTERISTICS   |                      |
|---|----------------------|
| OUTPUT CURRENT IN A TYPICAL 20 kHz MOTOR DRIVE                            |                      |
| $V_{CES}$   | 600 V                |
| $I_{RMS}$ per phase (1.94 kW total) with $T_C = 90\text{ }^\circ\text{C}$ | 6.7 $A_{RMS}$        |
| $T_J$   | 125 $^\circ\text{C}$ |
| Supply voltage  | 360 $V_{DC}$         |
| Power factor  | 0.8                  |
| Modulation depth (see fig. 1)   | 115 %                |
| $V_{CE(on)}$ (typical) at $I_C = 6.0\text{ A}$ , 25 $^\circ\text{C}$      | 1.72 V               |
| Speed   | 8 kHz to 30 kHz      |
| Package   | SIP                  |
| Circuit configuration   | Three phase inverter |

### FEATURES

- Short circuit rated ultrafast: optimized for high speed (see fig. 1 for current vs. frequency curve), and short circuit rated to 10  $\mu\text{s}$  at 125  $^\circ\text{C}$ ,  $V_{GE} = 15\text{ V}$
- Fully isolated printed circuit board mount package
- Switching-loss rating includes all “tail” losses
- HEXFRED<sup>®</sup> soft ultrafast diodes
- UL approved file E78996
- Designed and qualified for industrial level
- Material categorization: for definitions of compliance please see [www.vishay.com/doc?99912](http://www.vishay.com/doc?99912)


**RoHS  
COMPLIANT**

### DESCRIPTION

The IGBT technology is the key to Vishay’s Semiconductors advanced line of IMS (Insulated Metal Substrate) power modules. These modules are more efficient than comparable bipolar transistor modules, while at the same time having the simpler gate-drive requirements of the familiar power MOSFET. This superior technology has now been coupled to a state of the art materials system that maximizes power throughput with low thermal resistance. This package is highly suited to motor drive applications and where space is at a premium.

| ABSOLUTE MAXIMUM RATINGS                         |                |  |                         |                     |
|--|----------------|--|-------------------------|---------------------|
| PARAMETER  | SYMBOL         | TEST CONDITIONS  | MAX.                    | UNITS               |
| Collector to emitter voltage                     | $V_{CES}$      |  | 600                     | V                   |
| Continuous collector current, each IGBT          | $I_C$          | $T_C = 25\text{ }^\circ\text{C}$   | 11                      | A                   |
|  |                | $T_C = 100\text{ }^\circ\text{C}$  | 6.0                     |                     |
| Pulsed collector current                         | $I_{CM}$       | Repetitive rating; $V_{GE} = 20\text{ V}$ , pulse width limited by maximum junction temperature See fig. 20                | 22                      | A                   |
| Clamped inductive load current                   | $I_{LM}$       | $V_{CC} = 80\%$ ( $V_{CES}$ ), $V_{GE} = 20\text{ V}$ , $L = 10\text{ }\mu\text{H}$ , $R_G = 22\text{ }\Omega$ See fig. 19 | 22                      | A                   |
| Diode continuous forward current                 | $I_F$          | $T_C = 100\text{ }^\circ\text{C}$  | 6.1                     | A                   |
| Diode maximum forward current                    | $I_{FM}$       |  | 22                      | A                   |
| Short circuit withstand time                     | $t_{SC}$       |  | 10                      | $\mu\text{s}$       |
| Gate to emitter voltage                          | $V_{GE}$       |  | $\pm 20$                | V                   |
| Isolation voltage                                | $V_{ISOL}$     | Any terminal to case, $t = 1\text{ minute}$  | 2500                    | $V_{RMS}$           |
| Maximum power dissipation, each IGBT             | $P_D$          | $T_C = 25\text{ }^\circ\text{C}$   | 36                      | W                   |
|  |                | $T_C = 100\text{ }^\circ\text{C}$  | 14                      |                     |
| Operating junction and storage temperature range | $T_J, T_{Stg}$ |  | -40 to +150             | $^\circ\text{C}$    |
| Soldering temperature                            |                | For 10 s, (0.063" (1.6 mm) from case)  | 300                     |                     |
| Mounting torque                                  |                | 6-32 or M3 screw   | 5 to 7<br>(0.55 to 0.8) | lbf · in<br>(N · m) |



| THERMAL AND MECHANICAL SPECIFICATIONS                 |                     |      |      |       |
|---|---------------------|------|------|-------|
| PARAMETER   | SYMBOL              | TYP. | MAX. | UNITS |
| Junction-to-case, each IGBT, one IGBT in conduction   | $R_{thJC}$ (IGBT)   | -    | 3.5  | °C/W  |
| Junction-to-case, each diode, one diode in conduction | $R_{thJC}$ (DIODE)  | -    | 5.5  |       |
| Case to sink, flat, greased surface                   | $R_{thCS}$ (MODULE) | 0.10 | -    |       |
| Weight of module                                      |                     | 20   | -    | g     |
|   |                     | 0.7  | -    | oz.   |

| ELECTRICAL SPECIFICATIONS ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise specified) |                                 |   |   |      |           |               |   |
|--|---------------------------------|---|---|------|-----------|---------------|---|
| PARAMETER  | SYMBOL                          | TEST CONDITIONS   | MIN.                                    | TYP. | MAX.      | UNITS         |   |
| Collector to emitter breakdown voltage   | $V_{(BR)CES}$ <sup>(1)</sup>    | $V_{GE} = 0\text{ V}$ , $I_C = 250\text{ }\mu\text{A}$                              | 600                                     | -    | -         | V             |   |
| Temperature coeff. of breakdown voltage  | $\Delta V_{(BR)CES}/\Delta T_J$ | $V_{GE} = 0\text{ V}$ , $I_C = 1.0\text{ mA}$                                       | -                                       | 0.45 | -         | V/°C          |   |
| Collector to emitter saturation voltage  | $V_{CE(on)}$                    | $I_C = 6.0\text{ A}$  | $V_{GE} = 15\text{ V}$<br>See fig. 2, 5 | -    | 1.72      | 2.10          | V |
|  |                                 | $I_C = 11\text{ A}$   |   | -    | 2.00      | -             |   |
|  |                                 | $I_C = 6.0\text{ A}$ , $T_J = 150\text{ }^\circ\text{C}$                            |   | -    | 1.60      | -             |   |
| Gate threshold voltage   | $V_{GE(th)}$                    | $V_{CE} = V_{GE}$ , $I_C = 250\text{ }\mu\text{A}$                                  | 3.0                                     | -    | 6.0       |               |   |
| Temperature coeff. of threshold voltage  | $\Delta V_{GE(th)}/\Delta T_J$  |   | -                                       | -13  | -         | mV/°C         |   |
| Forward transconductance   | $g_{fe}$ <sup>(2)</sup>         | $V_{CE} = 100\text{ V}$ , $I_C = 12\text{ A}$                                       | 3.0                                     | 6.0  | -         | S             |   |
| Zero gate voltage collector current  | $I_{CES}$                       | $V_{GE} = 0\text{ V}$ , $V_{CE} = 600\text{ V}$                                     | -                                       | -    | 250       | $\mu\text{A}$ |   |
|  |                                 | $V_{GE} = 0\text{ V}$ , $V_{CE} = 600\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$ | -                                       | -    | 2500      |               |   |
| Diode forward voltage drop   | $V_{FM}$                        | $I_C = 12\text{ A}$   | See fig. 13                             | -    | 1.4       | 1.7           | V |
|  |                                 | $I_C = 12\text{ A}$ , $T_J = 150\text{ }^\circ\text{C}$                             |   | -    | 1.3       | 1.6           |   |
| Gate to emitter leakage current  | $I_{GES}$                       | $V_{GE} = \pm 20\text{ V}$  | -                                       | -    | $\pm 100$ | nA            |   |

Notes

- (1) Pulse width  $\leq 80\text{ }\mu\text{s}$ , duty factor  $\leq 0.1\%$
- (2) Pulse width  $5.0\text{ }\mu\text{s}$ ; single shot

| SWITCHING CHARACTERISTICS ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise specified) |                  |  |             |      |      |               |                  |
|--|------------------|--|-------------|------|------|---------------|------------------|
| PARAMETER  | SYMBOL           | TEST CONDITIONS  | MIN.        | TYP. | MAX. | UNITS         |                  |
| Total gate charge (turn-on)  | $Q_g$            | $I_C = 6\text{ A}$   | -           | 61   | 91   | nC            |                  |
| Gate to emitter charge (turn-on)   | $Q_{ge}$         | $V_{CC} = 400\text{ V}$  | -           | 7.4  | 11   |               |                  |
| Gate to collector charge (turn-on)   | $Q_{gc}$         | See fig. 8   | -           | 27   | 40   |               |                  |
| Turn-on delay time   | $t_{d(on)}$      | $T_J = 25\text{ }^\circ\text{C}$<br>$I_C = 6.0\text{ A}$ , $V_{CC} = 480\text{ V}$<br>$V_{GE} = 15\text{ V}$ , $R_G = 23\text{ }\Omega$<br>Energy losses include "tail" and diode reverse recovery<br>See fig. 9, 10, 18   | -           | 55   | -    | ns            |                  |
| Rise time  | $t_r$            |  | -           | 24   | -    |               |                  |
| Turn-off delay time  | $t_{d(off)}$     |  | -           | 107  | 160  |               |                  |
| Fall time  | $t_f$            |  | -           | 92   | 140  |               |                  |
| Turn-on switching loss   | $E_{on}$         |  | -           | 0.28 | -    |               |                  |
| Turn-off switching loss  | $E_{off}$        | -  | 0.10        | -    | mJ   |               |                  |
| Total switching loss   | $E_{ts}$         | -  | 0.39        | 0.50 |      |               |                  |
| Short circuit withstand time   | $t_{SC}$         | $V_{CC} = 360\text{ V}$ , $T_J = 125\text{ }^\circ\text{C}$<br>$V_{GE} = 15\text{ V}$ , $R_G = 23\text{ }\Omega$ , $V_{CPK} < 500\text{ V}$  | 10          | -    | -    | $\mu\text{s}$ |                  |
| Turn-on delay time   | $t_{d(on)}$      | $T_J = 150\text{ }^\circ\text{C}$<br>$I_C = 6.0\text{ A}$ , $V_{CC} = 480\text{ V}$<br>$V_{GE} = 15\text{ V}$ , $R_G = 23\text{ }\Omega$<br>Energy losses include "tail" and diode reverse recovery<br>See fig. 10, 11, 18 | -           | 54   | -    | ns            |                  |
| Rise time  | $t_r$            |  | -           | 24   | -    |               |                  |
| Turn-off delay time  | $t_{d(off)}$     |  | -           | 161  | -    |               |                  |
| Fall time  | $t_f$            |  | -           | 244  | -    |               |                  |
| Total switching loss   | $E_{ts}$         |  | -           | 0.60 | -    |               | mJ               |
| Input capacitance  | $C_{ies}$        | $V_{GE} = 0\text{ V}$<br>$V_{CC} = 30\text{ V}$<br>$f = 1.0\text{ MHz}$  | -           | 740  | -    | pF            |                  |
| Output capacitance   | $C_{oes}$        |  | See fig. 7  | -    | 100  |               | -                |
| Reverse transfer capacitance   | $C_{res}$        |  |             | -    | 9.3  |               | -                |
| Diode reverse recovery time  | $t_{rr}$         | $T_J = 25\text{ }^\circ\text{C}$   | See fig. 14 | -    | 42   | 60            | ns               |
|  |                  | $T_J = 125\text{ }^\circ\text{C}$  |             | -    | 80   | 120           |                  |
| Diode peak reverse recovery current  | $I_{rr}$         | $T_J = 25\text{ }^\circ\text{C}$   | See fig. 15 | -    | 3.5  | 6.0           | A                |
|  |                  | $T_J = 125\text{ }^\circ\text{C}$  |             | -    | 5.6  | 10            |                  |
| Diode reverse recovery charge  | $Q_{rr}$         | $T_J = 25\text{ }^\circ\text{C}$   | See fig. 16 | -    | 80   | 180           | nC               |
|  |                  | $T_J = 125\text{ }^\circ\text{C}$  |             | -    | 220  | 600           |                  |
| Diode peak rate of fall of recovery during $t_p$   | $dl_{(rec)M}/dt$ | $T_J = 25\text{ }^\circ\text{C}$   | See fig. 17 | -    | 180  | -             | A/ $\mu\text{s}$ |
|  |                  | $T_J = 125\text{ }^\circ\text{C}$  |             | -    | 120  | -             |                  |

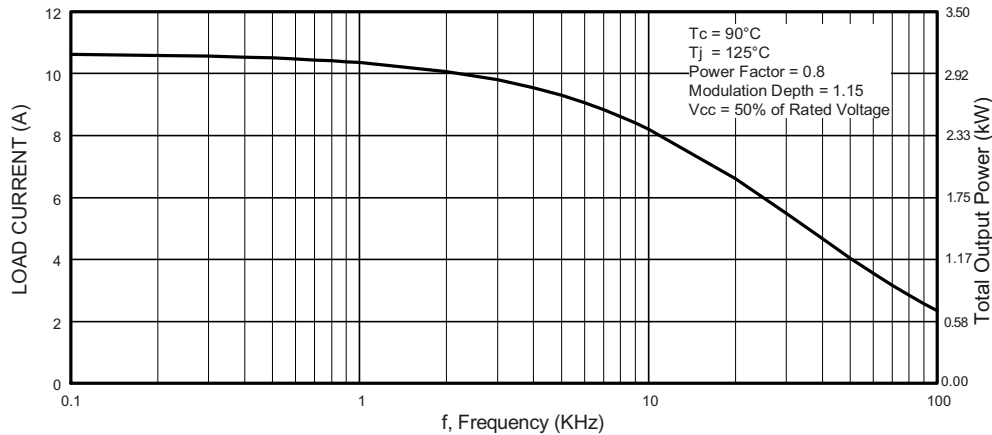


Fig. 1 - Typical Load Current vs. Frequency  
(Load Current =  $I_{RMS}$  of Fundamental)

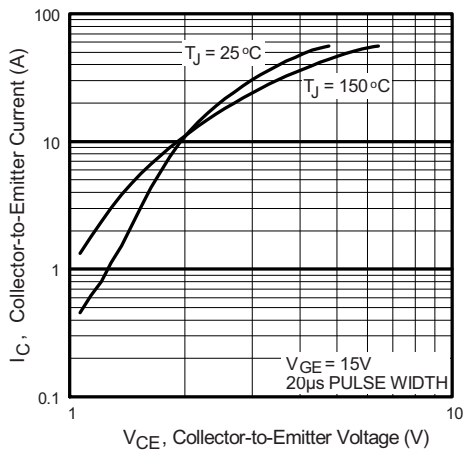


Fig. 2 - Typical Output Characteristics

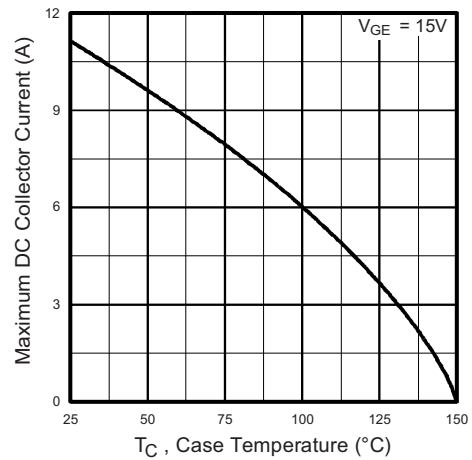


Fig. 4 - Maximum Collector Current vs. Case Temperature

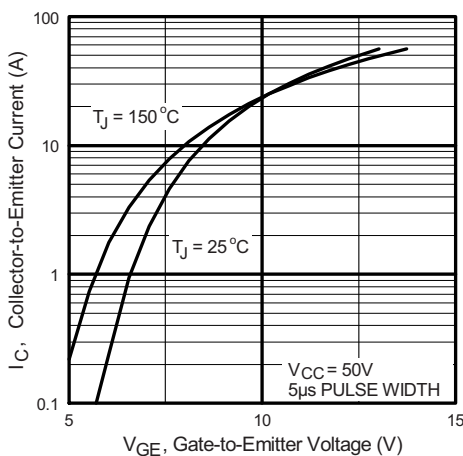


Fig. 3 - Typical Transfer Characteristics

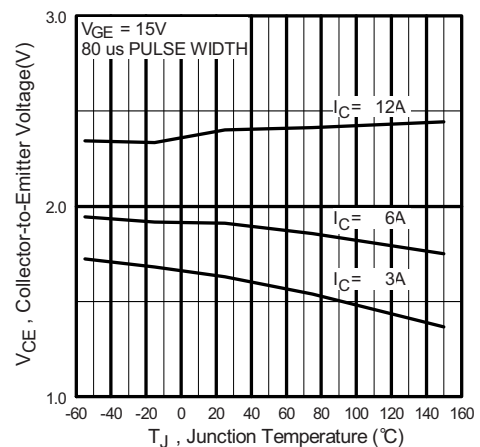


Fig. 5 - Typical Collector to Emitter Voltage vs. Junction Temperature

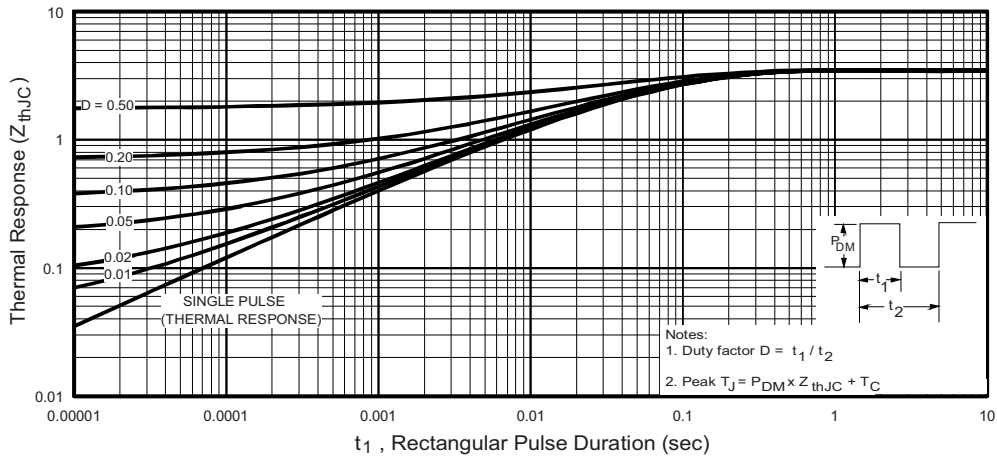


Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction to Case

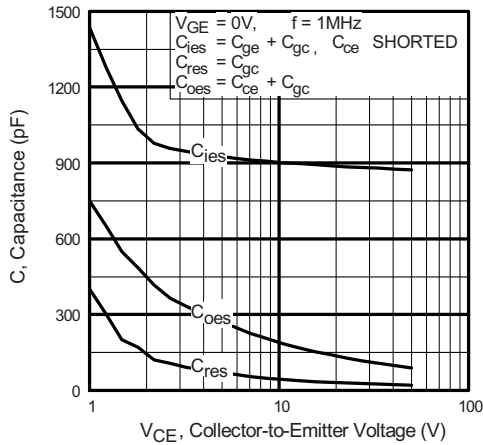


Fig. 7 - Typical Capacitance vs. Collector to Emitter Voltage

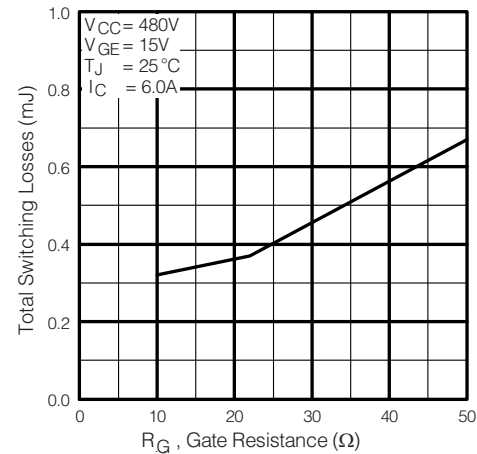


Fig. 9 - Typical Switching Losses vs. Gate Resistance

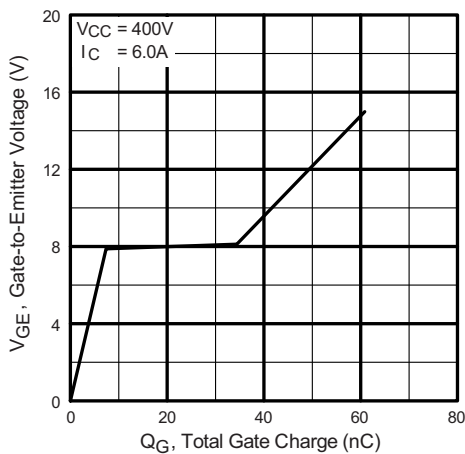


Fig. 8 - Typical Gate Charge vs. Gate to Emitter Voltage

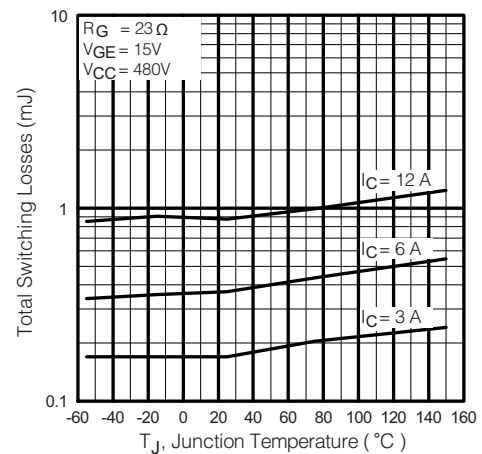


Fig. 10 - Typical Switching Losses vs. Junction Temperature

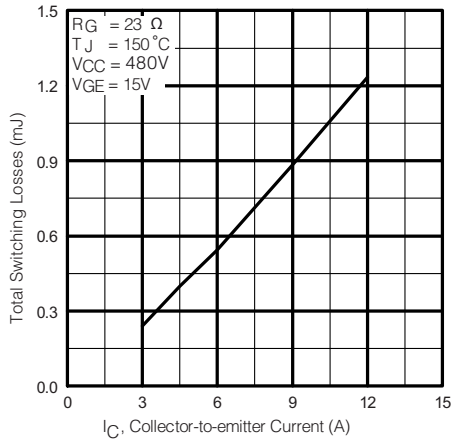


Fig. 11 - Typical Switching Losses vs. Collector to Emitter Current

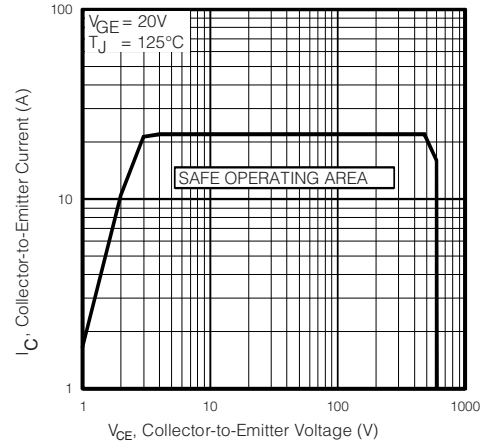


Fig. 12 - Turn-Off SOA

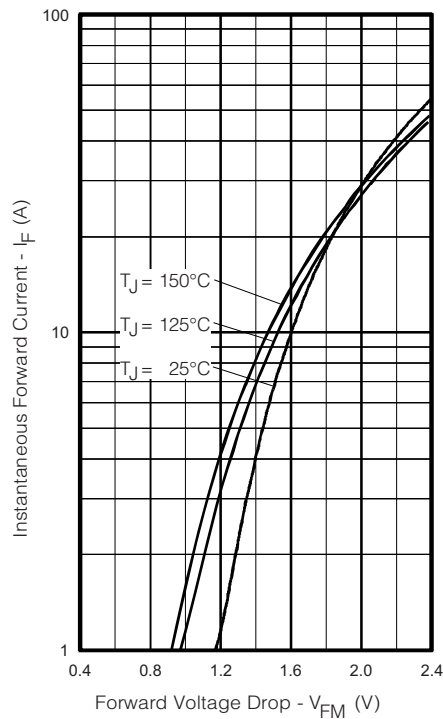


Fig. 13 - Maximum Forward Voltage Drop vs. Instantaneous Forward Current

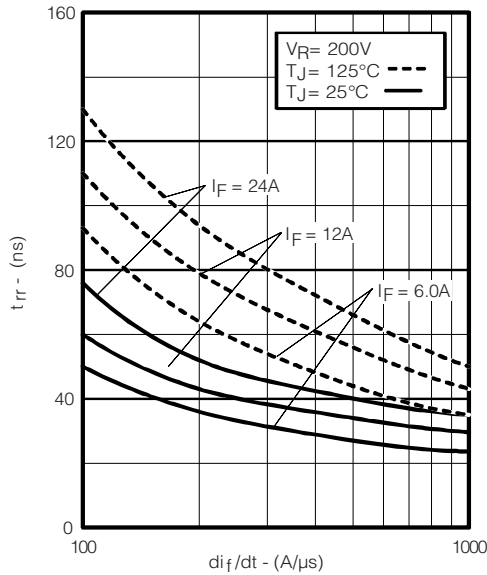


Fig. 14 - Typical Reverse Recovery Time vs.  $dI_F/dt$

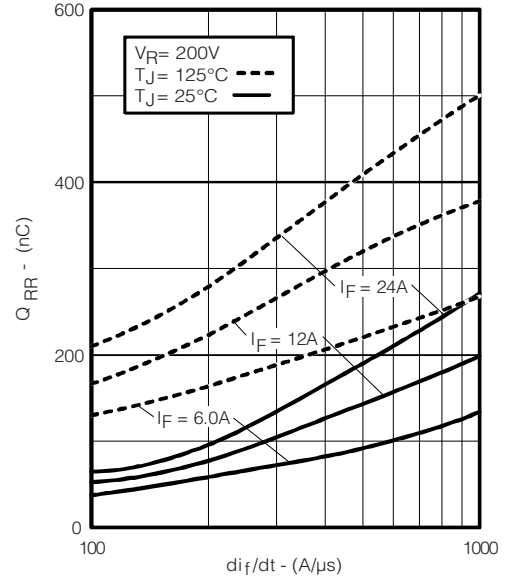


Fig. 16 - Typical Stored Charge vs.  $dI_F/dt$

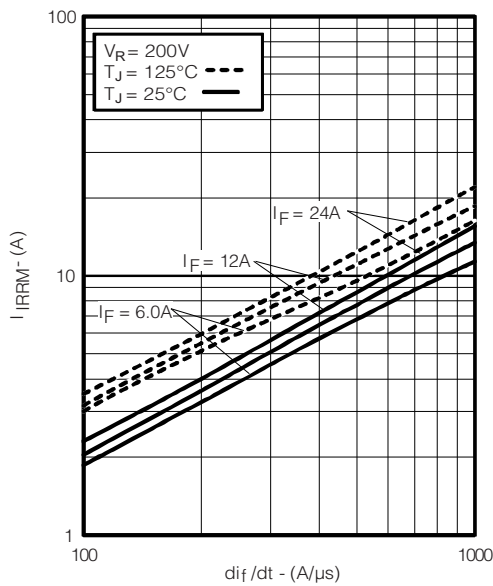


Fig. 15 - Typical Recovery Current vs.  $dI_F/dt$

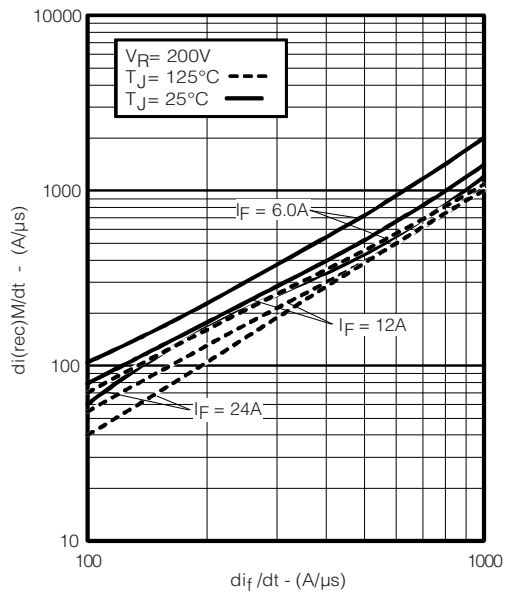


Fig. 17 - Typical  $dI_{(rec)M}/dt$  vs  $dI_F/dt$

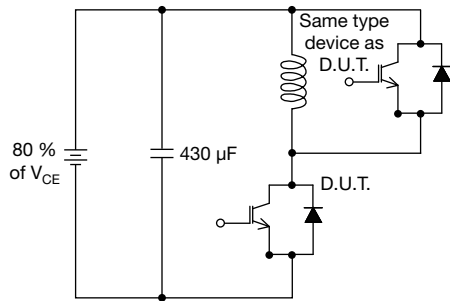


Fig. 18a - Test Circuit for Measurements of  $I_{LM}$ ,  $E_{on}$ ,  $E_{off(diode)}$ ,  $t_{tr}$ ,  $Q_{rr}$ ,  $I_{rr}$ ,  $t_{d(on)}$ ,  $t_r$ ,  $t_{d(off)}$ ,  $t_f$

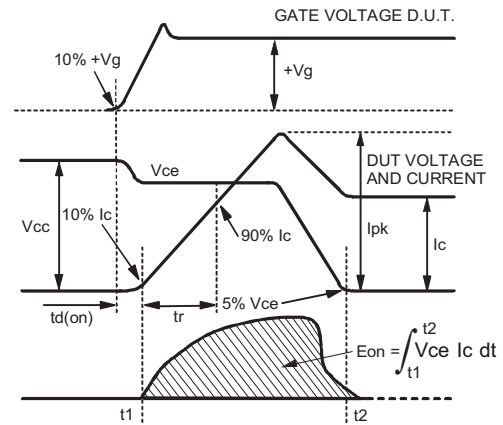


Fig. 18c - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{on}$ ,  $t_{d(on)}$ ,  $t_r$

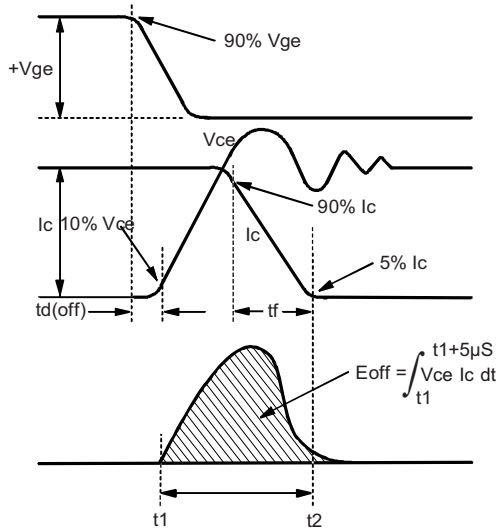


Fig. 18b - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{off}$ ,  $t_{d(off)}$ ,  $t_f$

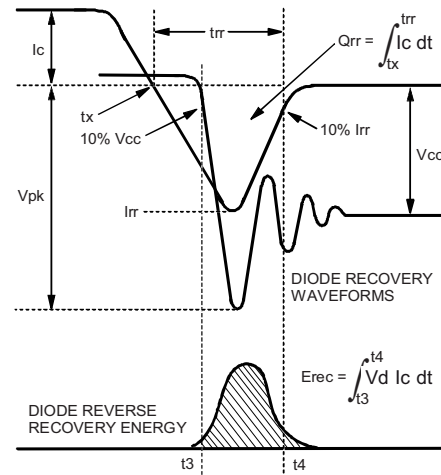


Fig. 18d - Test Waveforms for Circuit of Fig. 18a, Defining  $E_{rec}$ ,  $t_{rr}$ ,  $Q_{rr}$ ,  $I_{rr}$

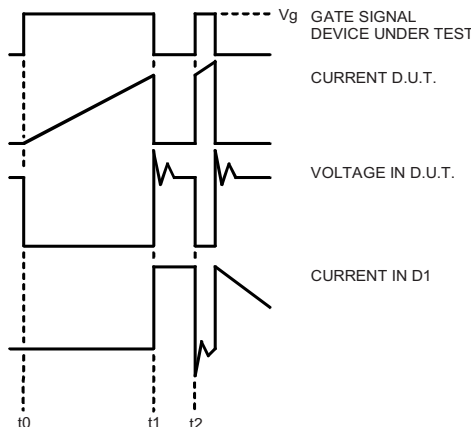


Fig. 18e - Macro Waveforms for Figure 18a's Test Circuit

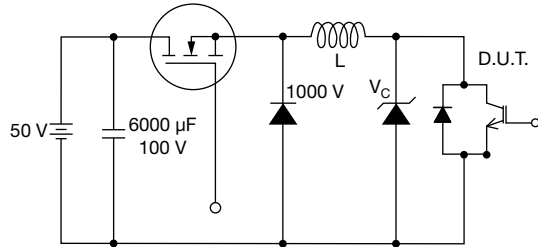


Fig. 19 - Clamped Inductive Load Test Circuit

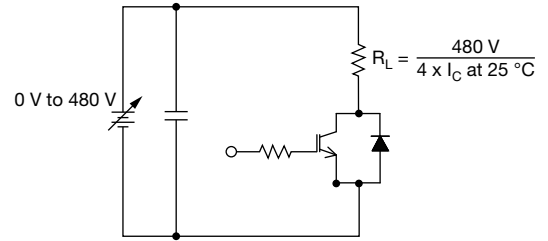
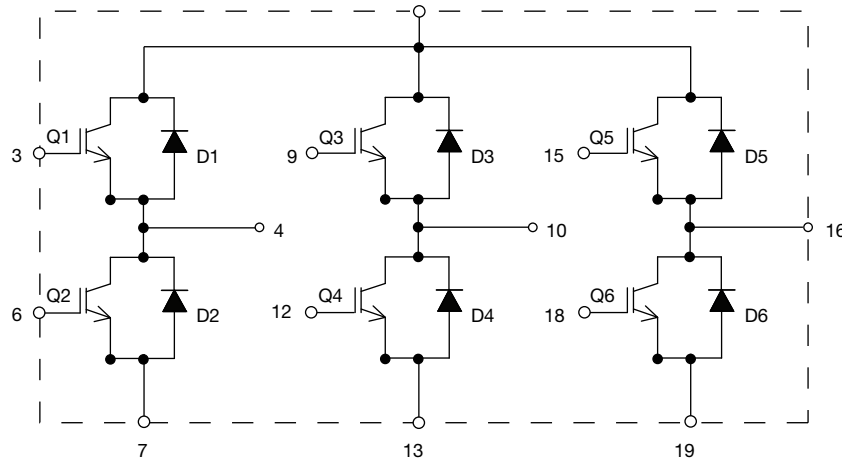


Fig. 20 - Pulsed Collector Current Test Circuit

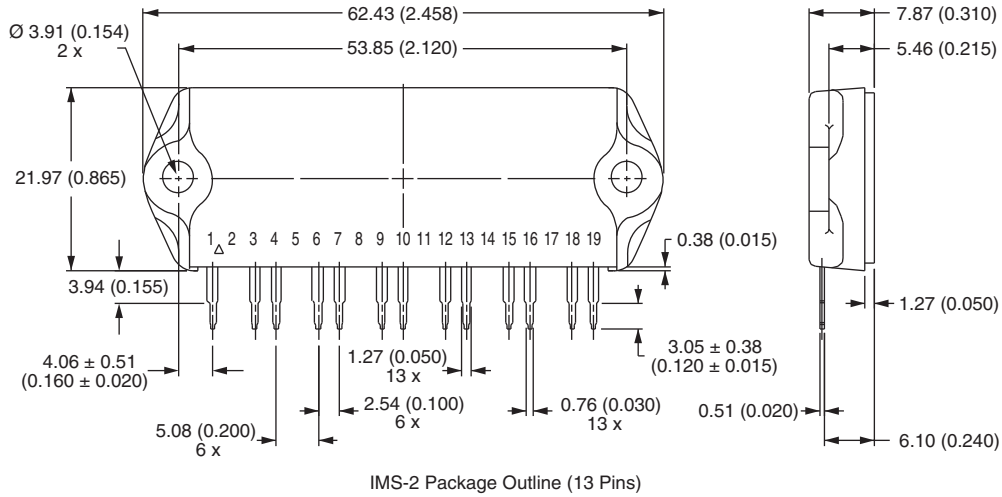
**CIRCUIT CONFIGURATION**

**LINKS TO RELATED DOCUMENTS**

|            |  |
|------------|--|
| Dimensions | <a href="http://www.vishay.com/doc?95066">www.vishay.com/doc?95066</a> |
|------------|--|



## IMS-2 (SIP)

**DIMENSIONS** in millimeters (inches)



**Notes**

- (1) Tolerance unless otherwise specified ± 0.254 mm (0.010")
- (2) Controlling dimension: inch
- (3) Terminal numbers are shown for reference only



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- Специальные условия для постоянных клиентов.
- Подбор аналогов.
- Поставку компонентов в любых объемах, удовлетворяющих вашим потребностям.
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- Комплексную поставку.
- Работу по проектам и поставку образцов.
- Формирование склада под заказчика.
- Сертификаты соответствия на поставляемую продукцию (по желанию клиента).
- Тестирование поставляемой продукции.
- Поставку компонентов, требующих военную и космическую приемку.
- Входной контроль качества.
- Наличие сертификата ISO.

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Конструкторский отдел помогает осуществить:

- Регистрацию проекта у производителя компонентов.
- Техническую поддержку проекта.
- Защиту от снятия компонента с производства.
- Оценку стоимости проекта по компонентам.
- Изготовление тестовой платы монтаж и пусконаладочные работы.



Тел: +7 (812) 336 43 04 (многоканальный)

Email: [org@lifeelectronics.ru](mailto:org@lifeelectronics.ru)